

The Pioneer for Sheet resistance/Resistivity measurement

# **Model: RT-70V series**

4 point probe sheet resistance/resistivity measurement system



### Combinational measurement system by RT-70V & Stage.

### Easy measurement handling & setting

#### **Features**

- Combinational measurement system by Measurement tester(RT-70V) & Stage.
- Thickness input with easy JOG dial operation (RT-70V Tester)
- Tester self-test function/Auto change-over measurement range function
- Thickness & Temperature correction function for Silicon sample
- Complies with the following ASTM & JIS

<JIS>: JIS H 0602-1995

JIS K 7194-1994

<ASTM>: ASTM F 84-99 (SEMI MF84)

ASTM F 374-00a ASTM F 390-11 ASTM F 1529-97

## Others (\*Please contact us for details)

sample

**Applications** 

(Silicon, Polysilicon, SiC etc)

Diffused sample (or layer)

#### **Sample Sizes**

\*Depends on each measurement stage type.
Please refer back side of this leaflet for details.

Semiconductor materilas, Solar-cell materials

New materials, functional materials (Carbon

nanotube, DLC, graphene, Ag nanowire etc)

Silicon-related epitaxial materials, Ion-implantation

Conductive thin film (Metal, ITO etc)

### **Measurement Range**

Test Item	Measurement Range
V/I Ratio	1.0m ~ 3.0M ohm
Sheet resistance	5.0m ~ 10.0M ohm/sq
Resistivity(Slice:0.01~9999.99μm)	1.0µ ~ 300.0k ohm.cm

A global leading company for resistivity measurement system.









RT-70V / RG-7C

(Tester + Auto[motor]probe up-down stroke stage)

Size; ~ 300mm(12 inch) Thickness; ~ 10mm



RT-70V / TS-7D

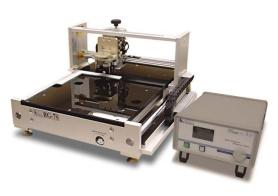
(Tester + Hand-held 4-point probe measurement unit) Size ; 20mm ~



**RT-70V / RG-5** 

(Tester + Manual[lever]probe up-down stroke stage)

Size; ~ 200mm(8 inch)
Thickness; ~ 10mm



#### **RT-70V / RG-7S**

(Tester + Manual X-Y & Auto Z axis stage)

Size; ~ 500 x 500mm Thickness; ~ 10mm

### **Measurement Accuracy / Repeatability**

Measurement Accuracy	Measurement Repeatability
%BIAS < ±1%	CV ≦ 0.7%
%BIAS = $\frac{\overline{X} - NISTguaranteedvalue}{NISTguaranteedvalue} \times 100[\%]$ $\overline{X}$ Average of same point x 10times measurement(23°C)	$CV = \frac{\sigma}{\overline{X}} \times 100[\%]$ $\sigma Standard deviation of same point                                    $

\*Measurement accuracy & repeatability as above are guaranteed values for Tester:RT-70V.

#### ☆ Please visit our website for the movie of this system.

- \*Please contact us for more details.
- \*The customers are always welcome to do Demo measurement.
- \*Specification subject to change without notice.



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